

Notice of References Cited	Application/Control No. 10/606,104		Applicant(s)/Patent Under Reexamination WANG ET AL.	
	Examiner Phillip Nguyen		Art Unit 2828	Page 1 of 1

U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-5,719,891	02-1998	Jewell, Jack L.	372/46.013
*	B	US-6,717,964 B2	04-2004	Jiang et al.	372/20
*	C	US-6,535,537 B1	03-2003	Kinoshita, Junichi	372/50.11
*	D	US-6,493,366 B1	12-2002	Johnson et al.	372/45.011
*	E	US-6,548,908 B2	04-2003	Chua et al.	257/773
*	F	US-6,940,885	09-2005	Cheng et al.	372/50.1
*	G	US-2003/0165171 A1	09-2003	Jewell, Jack L.	372/46
*	H	US-2002/0158265 A1	10-2002	Eisenbeiser, Kurt W.	257/98
*	I	US-2002/0084525 A1	07-2002	CHUA et al.	257/743
*	J	US-6,870,207 B2	03-2005	Taylor, Geoff W	257/217
*	K	US-6,782,021 B2	08-2004	Huang et al.	372/45.013
*	L	US-6,822,995 B2	11-2004	Kwon, Hoki	372/96
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	
	V	
	W	
	X	

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
 Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.